TOSHIBA Bipolar Linear Integrated Circuit Silicon Monolithic

TA75W393FU

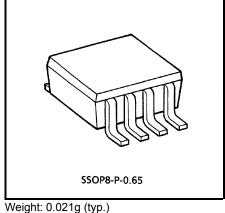
Dual Voltage Comparator

This device consist of two independent voltage comparators that designed to operate from a single power supply over a wide range of voltage.

Normal operation from dual supplies is also to be guaranteed on voltage range from \pm 1V to \pm 18V.

VCC is necessary at least more 1.5V volts than the input common mode voltage.

The output can be connected to other open collector outputs to achieve Wired-OR relation ship.



Features

Compatible to TA75393F.

Single supply voltage range or dual supplies : $2V_{DC}$ to $36V_{DC}$ or $\pm 1V_{DC}$ to $\pm 18V_{DC}$

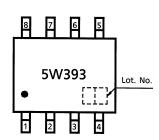
: 0.8mA (typ.) • Low supply current Low input offset voltage $\pm 2mV$ (typ.)

Wide input common mode voltage range : $0V_{DC}$ to $V_{CC} - 1.5V_{DC}$

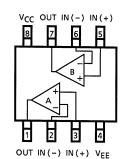
Output compatible with TTL, DTL, MOS and CMOS logic system.

The output can be connected to achieve Wired-OR relation..

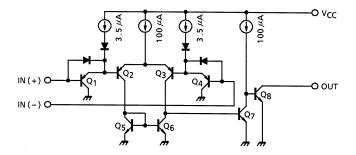
Marking (Top View)



Pin Connection (Top View)



Equivalent Circuit



Absolute Maximum Ratings (Ta = 25°C)

Characteristic	Symbol	Rating	Unit	
Supply voltage	V_{CC}, V_{EE}	±18 or 36	V	
Differential input voltage	DVIN	±36	٧	
Input voltage	V _{IN}	+0.3~V _{CC}	V	
Power dissipation	PD	250	mW	
Operating temperature	T _{opr}	-40~85	°C	
Storage temperature	T _{stg}	-55~125	°C	

Note: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings and the operating ranges.

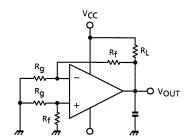
Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/"Derating Concept and Methods") and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

Electrical Characteristics (V_{CC} = 5V, V_{EE} = GND, Ta = 25°C)

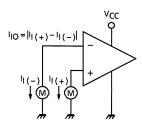
Characteristic	Symbol	Test Circuit	Test Condition	Min	Тур.	Max	Unit
Input offset voltage	V _{IO}	1	_	_	2	5	mV
Input bias current	lı	2	_	_	25	250	nA
Input offset current	I _{IO}	2	_	_	5	50	nA
Common mode input voltage	CMV _{IN}	_	_	0	_	V _{CC} -1.5	V
Supply current	Icc	3	No load	_	0.8	2	mA
Voltage gain	GV	_	R _L = 15kΩ	_	200	_	V/mA
Sink current	I _{sink}	4	IN (+) = 0V _{DC} , IN (-) = 1V _{DC} V _{OL} = 1.5V	6	16	_	nA
Output Voltage ("L" Level)	V _{OL}	5	$IN (+) = 0V_{DC}, IN (-) = 1V_{DC}$ $I_{sink} = 3mA$	_	0.2	0.4	V
Output Leak Current	ILEAK	_	$IN (+) = 1V_{DC}, IN (-) = 0V_{DC}$ $V_{O} = 5V_{DC}$	_	0.1	_	nA
Response Time	t _{rsp}	6	$R_L = 5.1k\Omega$, $C_L = 15pF$	_	1.3	_	μs

Test Circuit

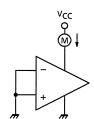
(1) V_{IO}



(2) I_I, I_{IO}



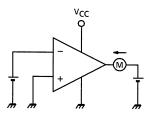
(3) I_{CC}



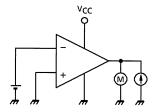
(4) I_{sink}

(6) t_{rsp}

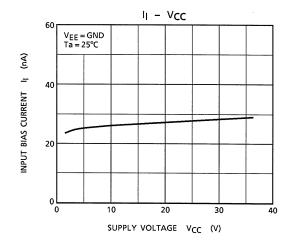
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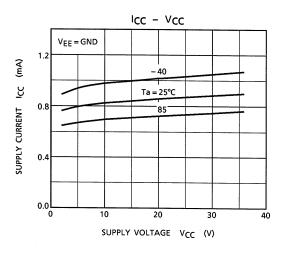


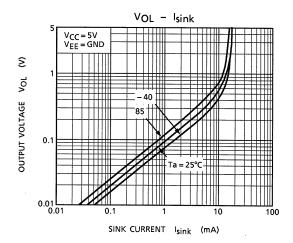
(5) V_{OL}

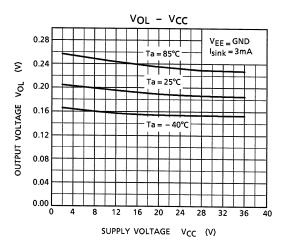


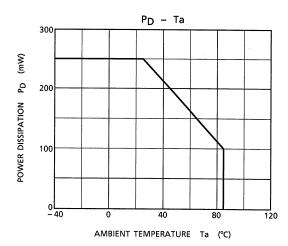
V_{IN} O







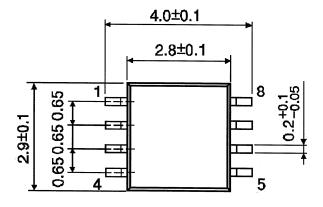


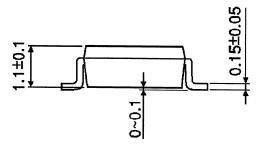


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Package Dimensions

SSOP8-P-0.65





Weight: 0.021g (typ.)

RESTRICTIONS ON PRODUCT USE

20070701-EN GENERAL

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